DOCUMENT CHANGE REQUEST

DCR number 1716	Changes required for: General	Originator: Steve Thacker
Date: 2026/10/26	Date sent: 2025/01/27	Organisation: ESCC Executive Secretariat
Status: IMPLEMENTED		

Title:	EVALUATION TEST PROGRAMME FOR INTEGRATED CIRCUITS: MONOLITHIC AND MULTICHIP		
Number:	2269000	Issue:	8

Other documents affected:

22900-6

Page:

As per attached spec mark-ups

Paragraph:

As per attached spec mark-ups

Original wording:

As per current spec issue above

Proposed wording:

ESCC 22900 & one example ancillary basic i.e. 2269000, are proposed to be amended in line with a request from the PSWG in order to test/review how best to proceed with suitable changes to all impacted ESCC specs:
i.e.
"PSWG would like to remove from ESCC 22900 all the information related to evaluation and qualification and to transfer it in the basic for evaluation and in the generic."
...
In addition, the PSWG stated:
"we are changing the test for TID in this way:
- For evaluation: 2 intermediate steps during evaluation whose level are to be agreed with the “qualifying agency” plus the overtest (e.g. 100 krad(Si) : 25 krad(Si), 50 krad(Si), 100 krad(Si) and 150 krad(Si).

- For qualification, MOQ or LAT: 1 level (the guaranteed one) for lot testing "
.....

In order to progress this PSWG review item, initial draft revisions of both 22900 & 2269000 have been prepared; see attached.:
22900 Draft 6
2269000 Draft 9

Justification:

This DCR is raised on behalf of the ESA & the PSWG

Attachments:
escc2269000iss9_draft_a_in_prog.docx, escc22900iss6_draft_a_in_prog.docx
Modifications:
N/A
Approval signature:

Date signed:
2026-10-26